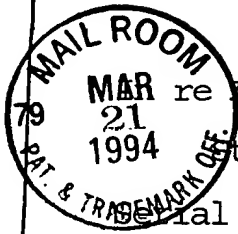


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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of:

Steve W. Heppler

Serial No.: 08/046,246

Filed: April 13, 1993

For: **METHOD AND APPARATUS FOR
TESTING OPENS AND SHORTS
ON INTEGRATED CIRCUITS
COMING OFF OF A
SINGULATION STATION**

Docket No.: 92-476

Paper No.: 4

Group Art Unit: 3101

Examiner: T. Nguyen

RECEIVED
MAR 25 1994
GROUP 310

March 18, 1994

Commissioner of Patents and Trademarks
Washington, D.C. 20231

Dear Commissioner:

AMENDMENT

In response to the Examiner's outstanding Office Action,
mailed December 21, 1993, please amend the application as follows:

In the Title:

Kindly change the Title to the following:

-- METHOD AND APPARATUS FOR TESTING AN INTEGRATED CIRCUIT --.

In the abstract:

On line 4 after "IC" please insert --(integrated circuit)--.

In the specification:

Page 3, line 8, after invention kindly insert the following
paragraph:

-- The invention is a method and an apparatus for controlling
positioning of a circuit before, during and after a circuit

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Micron Semiconductor, Inc.

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92-476